


<b>Search Notes</b> 	<b>Application/Control No.</b> 10572085	<b>Applicant(s)/Patent Under Reexamination</b> SHIN ET AL.
	<b>Examiner</b> ZEWDU BEYEN	<b>Art Unit</b> 2416

SEARCHED			
Class	Subclass	Date	Examiner
370	395.54	20090619	zb
709	222-229(text only)	20090619	zb

SEARCH NOTES		
Search Notes	Date	Examiner
I did inventor search on PLAM	20090619	ZB
Database used ---EAST (US-PGPUB,USPAT,FPRS,EPO,JPO,DERWENT)	20090619	ZB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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